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Contents

Invited Papers	Hunsperger, R.G., see Mentzer, M.A., et al
Para D. I. Vaine I. I. Laur Indused Continual Recording in	Iacopini, E., Stefanini, G., Zavattini, E.: Effects of a Magnetic
Broer, D.J., Vriens, L.: Laser-Induced Optical Recording in	Field on the Optical Properties of Dielectric Mirrors 63
Thin Films. Modelling of the Hole Opening and Experi-	Iqbal, M.Z., see Butt, M.A
ments with Organic Sublayers	Jenkinson, H.A., see Mentzer, M.A., et al
Güttler, W., see Richter, K.H., et al	Joyce, B.A., see Neave, J.H., et al
Richter, K.H., Güttler, W., Schwoerer, M.: UV-Holographic	Kazes, E., see Sujatha, N., et al 55
Gratings in TS-Diacetylene Single Crystals. Spatial Resolu-	Kindl, P., see Puff, W., et al
tion and Sensitivity	Knecht, J., see Künzel, H., et al 69
Riesterer, T., see Schlapbach, L	Kohn, S., see Olmstead, M.A., et al
Schlapbach, L., Riesterer, T.: The Activation of FeTi for	Krätzig, E., see Vollmer, J., et al
Hydrogen Absorption	Kreuer, K.D., Rabenau, A., Messer, R.: Proton Conductivity in
Schwoerer, M., see Richter, K.H., et al	the Layer Compound H ₃ OUO ₂ AsO ₄ · 3 H ₂ O (HU As). I.
Vriens, L., see Broer, D.J	Conductivity in the Orthorhombic Low-Temperature Phase
	and the Vehicle Mechanism of Proton Transport in Solids . 45
Contributed Papers	Kreuer, K.D., Rabenau, A., Messer, R.: Proton Conductivity
Constitution & apolis	in the Layer Compound H ₃ OUO ₂ AsO ₄ · 3H ₂ O (HUAs).
Amer, N.M., see Olmstead, M.A., et al	II. Conductivity in the Tetragonal High Temperature Phase 155
Baltz, R. von, Lingenfelder, Ch., Rupp, R.: Nonlocal Photo-	Künzel, H., Fischer, A., Knecht, J., Ploog, K.: Investigation of
voltaic Response Function for the Interpretation of Holo-	Persistent Photoconductivity in Si-Doped n-Al _x Ga _{1-x} As
gram Writing in Ferroelectric Crystals	Grown by Molecular Beam Epitaxy
Basu, P.K., see Saha, N.R., et al	Lingenfelder, Ch., see Baltz, R. von, et al
Bhardwaj, R.P., Nagpaul, K.K., Quamara, J.K., Sharma, B.L.:	Lynn, K.G., see Vehanen, A., et al
On the Occurrence of an Excitation-Effect in Pyromellit-	Maass, W., Duschl, M., Hoffmann, H., Friedlaender, F.J.:
imide Thin Film	A New Model for the Explanation of the Saturation
Boccara, A.C., see Olmstead, M.A., et al. 141	Buildup in the Transverse HGMS-Configuration 79
Butt, M.A., Iqbal, M.Z.: "0.75 eV Killer Centre" in Red-	Mascher, P., see Puff, W., et al
Emitting GaP LEDs	Massies, J., Sauvage-Simkin, M.: Mismatch and Electron
Chattopadhyay, D., see Deb Roy M., et al	
Cutler, P.H., see Sujatha, N., et al	Mobility in MBE Ga _x In _{1-x} As Epitaxial Layers on InP Substrates
Dawson, P., see Neave, J.H., et al	Mentzer, M.A., Hunsperger, R.G., Zavada, J.M., Jenkinson,
Deb Roy, M., Nag, B.R., Chattopadhyay, D.: High-Field	H.A., Gavanis, T.J.: Temperature Processing Effects in Proton-Implanted <i>n</i> -Type GaAs
Transport Properties of In _{0.765} Ga _{0.235} As _{0.5} P _{0.5}	Messer, R., see Kreuer, K.D., et al
	Messer, R., see Kreuer, K.D., et al
Dunn, B., see Farrington, G.C., et al	Miranda, L.C.M.: On the Use of the Thermal Lens Effect as a
	Thermo-Optical Spectroscopy of Solids
Eldrup, M., see Vehanen, A., et al	Miskovsky, N.M., see Sujatha, N., et al
Falcone, G., Oliva, A.: Energy Spectra of Atoms Sputtered	
by KeV Light-Ion Bombardment	Nag, B.R., see Deb Roy, M., et al. 39 Nagpaul, K.K., see Bhardwaj, R.P., et al. 211
Farrington, G.C., Dunn, B., Thomas, J.O.: The Lanthanide β"	Neave, J.H., Dobson, P.J., Harris, J.J., Dawson, P., Joyce, B.A.:
Aluminas. A New Family of Fluorescent Solid Electrolytes 159	Silicon Doping of MBE-Grown GaAs Films
Fauchet, P.M., Siegman, A.E.: Observations of Higher-Order Laser-Induced Surface Ripples on (111) Germanium 135	Nieminen, R.M., see Valkealahti, S
	Nisius, J.P., see Vollmer, J., et al. 125
	Nonomura, S., Okamoto, H., Hamakawa, Y.: A Study of
Fournier, D., see Olmstead, M.A., et al	
Friedlaender, F.J., see Maass, W., et al	Built-in Potential in a-Si Solar Cells by Means of Back- Surface Reflected Electroabsorption
Fritzsche, C.R., Rothemund, W.: The Lateral Extension of	
Radiation Damage in Ion-Implanted Semiconductors 129	
Gabla, L., see Pedrys, R	Olmstead, M.A., Amer, N.M., Kohn, S., Fournier, D., Boccara,
Gavanis, T.J., see Mentzer, M.A., et al	A.C.: Photothermal Displacement Spectroscopy: An Optical Probe for Solids and Surfaces
Hamakawa, Y., see Nonomura, S., et al	
Harris, J.J., see Neave, J.H., et al	Oliva, A., see Falcone, G
Hertel, P., see Vollmer, J., et al	Pedrys, R., Gabla, L.: Photon Emission from Sputtered Nickel
Hoffmann, H., see Maass, W., et al	Atoms as a Function of Target Temperature Near the Curie
Hora, H.: Stresses in Silicon Crystals from Ion-Implanted	Point
Amorphous Regions	Ploog, K., see Künzel, H., et al

Puff, W., Mascher, P., Kindl, P., Sormann, H.: On the Temperature Dependence of Positron Lifetimes in Tin and the	Sormann, H., see Puff, W., et al. 183 Stefanini, G., see Iacopini, E., et al. 63
Transition from the β - to the α -Phase	Sujatha, N., Cutler, P.H., Kazes, E., Rogers, J.P., Miskovsky,
Quamara, J.K., see Bhardwaj, R.P., et al	N.M.: Variational Formulation for the Equilibrium Con-
Rabenau, A., see Kreuer, K.D., et al	dition of a Conducting Fluid in an Electric Field 55
Rabenau, A., see Kreuer, K.D., et al	Thomas, J.O., see Farrington, G.C., et al
Rogers, J.P., see Sujatha, N., et al 55	Valkealahti, S., Nieminen, R.M.: Monte-Carlo Calculations of
Rothemund, W., see Fritzsche, C.R	keV Electron and Positron Slowing Down in Solids 95
Roychoudhury, D., see Saha, N.R., et al	Vehanen, A., Lynn, K.G., Schultz, P.J., Eldrup, M.: Improved
Rupp, R., see Baltz, R. von, et al	Slow-Positron Yield Using a Single Crystal Tungsten
Saha, N.R., Roychoudhury, D., Basu, P.K.: Analytical Study	Moderator
of the Performance of minSIS Solar Cells with a Back	Vollmer, J., Nisius, J.P., Hertel, P., Krätzig, E.: Refractive
Surface Field	Index Profiles of LiNbO ₃ :Ti Waveguides
Sauvage-Simkin, M., see Massies, J	Zavada, J.M., see Mentzer, M.A., et al
Schultz, P.J., see Vehanen, A., et al	Zavattini, E., see Iacopini, E., et al
Sharma, B.L., see Bhardwaj, R.P., et al	
Siegman, A.E., see Fauchet, P.M	Indexed in Current Contents

